Nuclear Instruments and Methods in Physics Research B50 (1990) 481–488
North-Holland

AUTHOR INDEX

Agulló-López, F., see Rebouta, L. B50 (1990) 428
Al-Juwair, H.A., M.M. Al-Kofahi, A.B. Hallak and M. Rajeh, A 3 MV Tandetron facility at KFUPM B50 (1990) 474
Al-Kofahi, M.M., see Al-Juwair, H.A. B50 (1990) 474
Anthony, J.M., S.E. Matteson, D.K. Marble, J.L. Duggan, F.C. McDaniel and D.J. Donahue, Applications of accelerator mass spectrometry to electronic materials B50 (1990) 262
Apostolakis, D., see Georgiadis, A.P. B50 (1990) 321
Arafah, D.E., see Meyer, J.D. B50 (1990) 109

Bajt, S., see Przybyłowicz, W. B50 (1990) 231
Bakraji, E.H., A. Giovagnoli, G. Blondiaux and J.-L. Debrun, Charged-particle activation methods for the analysis of carbon and oxygen in high-purity gallium B50 (1990) 65
Bange, K., see Wagner, W. B50 (1990) 27
Baraldi, D., see Bizzarri, U. B50 (1990) 331
Barbosa, M., see Da Silva, R.C. B50 (1990) 423
Barranco, F., see Respaldiza, M.A. B50 (1990) 226
Barrett, J.H., see Van Ijzendoorn, L.J. B50 (1990) 127
Bauer, W., J. Briggmann, H.-D. Carstanjen, S. Connell, W. Decker, J. Diehl, K. Maier, J. Major, H.-E. Schaefer, A. Seeger, H. Stoll and E. Widmann, The Stuttgart positron beam, its performance and recent experiments . B50 (1990) 300
Baumann, H., see Roland, G. B50 (1990) 145
Baumann, H., see Stanescu, T.M. B50 (1990) 167
Baumann, H., see Fröhlich, O. B50 (1990) 436
Baumann, H., see Hofmann, D. B50 (1990) 478
Baumgärtner, M., U. Emmerling, W. Ernst, E. Finckh, G. Fuchs, F. Gumbmann, M. Haller, R. Höpfl, R. Karschnick, W. Kretschmer, A. Rauscher, M. Schleicher and W. Schuster, A new AMS beam line at the Erlangen tandem accelerator facility B50 (1990) 286
Behrisch, R., see Reichle, R. B50 (1990) 68
Beier, T., see Weber, J. B50 (1990) 221
Bergmeister, F.-J., see Osipowicz, T. B50 (1990) 238
Berkovits, D., see Boaretto, E. B50 (1990) 280
Bethge, K., see Köhl, F. B50 (1990) 19
Bethge, K., see Mader, A. B50 (1990) 35
Bethge, K., see Roland, G. B50 (1990) 145
Bethge, K., see Stanescu, T.M. B50 (1990) 167
Bethge, K., see Fröhlich, O. B50 (1990) 436
Bethge, K., see Hofmann, D. B50 (1990) 478
Bezuidenhout, D., see Pretorius, R. B50 (1990) 105
Bibić, N., see Milosavljević, M. B50 (1990) 391
Bittner, U., see Müller, D. B50 (1990) 271
Bizzarri, U., G. Giubileo, G. Messina, L. Picardi, P. Raimondi, C. Ronsivalle, A. Vignati, D. Baraldi, A.M. Castagnola, S. Omarini, L. Fabiani and V. Leoni, Electron accelerators at the ENEA Center at Frascati: Development and application B50 (1990) 331
Blain, M.G., see Schweikert, E.A. B50 (1990) 307
Blondiaux, G., see Bakraji, E.H. B50 (1990) 65
Boaretto, E., D. Berkovits, G. Hollos and M. Paul, Measurements of natural concentrations of ^{129}I in uranium ores by accelerator mass spectrometry B50 (1990) 280
Bodart, F., see Lucas, S. B50 (1990) 401
Boebel, O., see Steiger, J. B50 (1990) 31
Boerma, D.O., Materials analysis using ion beam techniques B50 (1990) 77
Boerma, D.O., F. Labohm and J.A. Reinders, Design of a magnetic spectrograph for surface, interface and thin-layer analysis B50 (1990) 291
Bolse, W., see Lieb, K.P. B50 (1990) 10
Bolse, W., see Weber, T. B50 (1990) 95
Bolse, W., T. Weber and W. Lohmann, Ion beam mixing of titanium films on stainless steel B50 (1990) 416

0168-583X/90/$03.50 © Elsevier Science Publishers B.V.
(North-Holland)

Bombelka, E., see Wätjen, U. . . . B50 (1990) 172
Boni, C., A. Caridi, E. Cereda, G.M. Braga Marcazzan, F. Parmigiani and M. Scagliotti, Determination of the Li/Ni ratio in $Li_xNi_{1-x}O$ thin films by PIXE–PIGE analysis . . . B50 (1990) 243
Boreli, F., see Stojanović, M.S. . . . B50 (1990) 102
Bradshaw, F.J., see Cohen, D.D. . . . B50 (1990) 43
Bradshaw, S.D., see Cohen, D.D. . . . B50 (1990) 43
Braga Marcazzan, G.M., see Cereda, E. . . . B50 (1990) 48
Braga Marcazzan, G.M., see Boni, C. . . . B50 (1990) 243
Breese, M.B.H., see Cookson, J.A. . . . B50 (1990) 208
Briere, M., see Steiger, J. . . . B50 (1990) 31
Briggmann, J., see Bauer, W. . . . B50 (1990) 300
Buchal, C., see Lubig, A. . . . B50 (1990) 114

Campbell, J.L., W.J. Teesdale and J.-X. Wang, Accuracy of thick-target micro-PIXE analysis . . . B50 (1990) 189
Caridi, A., see Boni, C. . . . B50 (1990) 243
Carstanjen, H.-D., see Bauer, W. . . . B50 (1990) 300
Castagnola, A.M., see Bizzarri, U. . . . B50 (1990) 331
Cereda, E., G.M. Braga Marcazzan, F. Parmigiani and M. Scagliotti, An RBS, NRA and SEM study of annealing effects on the microstructure of palladium layers . . . B50 (1990) 48
Cereda, E., see Boni, C. . . . B50 (1990) 243
Chevarier, A., see El Bouanani, M. . . . B50 (1990) 431
Chevarier, N., see El Bouanani, M. . . . B50 (1990) 431
Cichocki, T., see Rokita, E. . . . B50 (1990) 217
Cohen, D.D., S.D. Bradshaw, F.J. Bradshaw and A. Katsaros, Determination of ^{18}O concentrations in microsamples of biological fluids . . . B50 (1990) 43
Connell, S., see Bauer, W. . . . B50 (1990) 300
Cookson, J.A. and M.B.H. Breese, Materials applications of nuclear microprobes . . . B50 (1990) 208
Corts, T., see Lieb, K.P. . . . B50 (1990) 10
Corts, T., see Osipowicz, T. . . . B50 (1990) 238
Costantini, J.M., see Tirira, J. . . . B50 (1990) 135
Craig, S., see Hare, G. . . . B50 (1990) 470

Da Silva, M.F., see Da Silva, R.C. . . . B50 (1990) 423
Da Silva, M.F., see Rebouta, L. . . . B50 (1990) 428
Da Silva, R.C., M.F. Da Silva, A.A. Melo, J.C. Soares, E. Leitão and M. Barbosa, Diffusion and corrosion behaviour of tungsten-implanted aluminium and the $Al_{12}W$ phase . . . B50 (1990) 423
Da Silveira, E.F., see Schweikert, E.A. . . . B50 (1990) 307
Dearnaley, G., Ion beam modification of metals . . . B50 (1990) 358
Debrun, J.-L., see Bakraji, E.H. . . . B50 (1990) 65
Decker, W., see Bauer, W. . . . B50 (1990) 300
Demortier, G., see Mathot, S. . . . B50 (1990) 52
Denissen, C.J.M., see Johansen, A. . . . B50 (1990) 119
Devoti, R., see Tuniz, C. . . . B50 (1990) 338
Diéguez, E., see Rebouta, L. . . . B50 (1990) 428
Diehl, J., see Bauer, W. . . . B50 (1990) 300
Diehl, U., see Weber, J. . . . B50 (1990) 221
Ditrói, F., S. Takács, I. Mahunka and Z. Gémesi, Trace-element study of glass samples by using activation methods . . . B50 (1990) 62
Divoux, S., see Rokita, E. . . . B50 (1990) 217
Donahue, D.J., see Anthony, J.M. . . . B50 (1990) 262
Donnet, C., H. Jaffrezic, G. Marest, N. Moncoffre and J. Tousset, Iron-implanted sintered alumina studied by RBS, CEMS and SEM techniques . . . B50 (1990) 410
Duggan, J.L., see Anthony, J.M. . . . B50 (1990) 262

Earwaker, L.G., see Sokhi, R.S. . . . B50 (1990) 140
Ebel, F., W. Faust, C. Hahn, M. Rückert, H. Schneider, A. Singe and I. Tobehn, Research at the positron source TEPOS . . . B50 (1990) 328
El Bouanani, M., A. Chevarier, N. Chevarier, E. Gerlic, H. Jaffrezic and M. Stern, Argon irradiation damage at a Cu/Al_2O_3 interface for different alumina structures . . . B50 (1990) 431
El Khakani, M.A., H. Jaffrezic, G. Marest, N. Moncoffre and J. Tousset, Sputtering yield and residual vacuum influence during titanium implantation into iron . . . B50 (1990) 406

Emmerling, U., see Baumgärtner, M. B50 (1990) 286
Engelmann, C., see Trocellier, P. B50 (1990) 247
Ernst, W., see Baumgärtner, M. B50 (1990) 286

Fabiani, L., see Bizzarri, U. B50 (1990) 331
Faestermann, H., K. Kato, G. Korschinek, P. Krauthan, E. Nolte, W. Rühm and L. Zerle, Accelerator mass spectrometry with fully stripped ^{26}Al, ^{36}Cl, ^{41}Ca and ^{59}Ni ions B50 (1990) 275
Faestermann, T., see Müller, D. B50 (1990) 271
Faust, W., see Ebel, F. B50 (1990) 328
Finckh, E., see Baumgärtner, M. B50 (1990) 286
Findlay, D.J.S., Applications of photonuclear reactions B50 (1990) 314
Fink, D., see Gebauer, B. B50 (1990) 159
Fischer, B.E., see Klein, S.S. B50 (1990) 150
Freudenberger, C., see Hofmann, D. B50 (1990) 478
Fritzsche, S., A.M.M. Mohammedein, G. Musiol, I. Reiche, F. Schubert and G. Zschornack, Atomic data for accelerator-based X-ray fluorescence spectroscopy B50 (1990) 353
Fröhlich, O., H. Baumann and K. Bethge, Angular dependence of the self-ion-sputtering yield of silicon at 30 keV B50 (1990) 436
Fröhlingsdorf, J., see Lubig, A. B50 (1990) 114
Frontier, J.P., see Tirira, J. B50 (1990) 135
Fuchs, G., see Baumgärtner, M. B50 (1990) 286

Gärtner, K., see Götz, G. B50 (1990) 131
Gebauer, B., D. Fink, P. Goppelt, M. Wilpert and T.H. Wilpert, Multidimensional ERDA measurements and depth profiling of medium-heavy elements B50 (1990) 159
Gemende, B., see Lück, H.B. B50 (1990) 395
Gémesi, Z., see Ditrói, F. B50 (1990) 62
Georgiadis, A.P., D. Apostolakis, M. Vourkas and A. Pape, Sensitivity of trace-element analysis by X-ray emission induced by 0.1–10 MeV electrons B50 (1990) 321
Gerlic, E., see El Bouanani, M. B50 (1990) 431
Gerritsen, E., see Johansen, A. B50 (1990) 119
Gilberd, P.W., see Sokhi, R.S. B50 (1990) 140
Gillitzer, A., see Müller, D. B50 (1990) 271
Giovagnoli, A., see Bakraji, E.H. B50 (1990) 65
Giubileo, G., see Bizzarri, U. B50 (1990) 331
Gómez-Camacho, J., see Respaldiza, M.A. B50 (1990) 226
Gómez-Tubío, B.M., see Respaldiza, M.A. B50 (1990) 226
Gonsior, B., see Rokita, E. B50 (1990) 217
Goppelt, P., see Gebauer, B. B50 (1990) 159
Gosset, J., see Trocellier, P. B50 (1990) 247
Götz, G., K. Gärtner and W. Wesch, Investigation of point defects by temperature-dependent dechanneling . . . B50 (1990) 131
Grambole, D., see Neelmeijer, C. B50 (1990) 439
Grime, G.W. and F. Watt, Nuclear microscopy – elemental mapping using high-energy ion beam techniques . . B50 (1990) 197
Gumbmann, F., see Baumgärtner, M. B50 (1990) 286
Günzler, R., see Maisch, T. B50 (1990) 1
Gwilliam, R.M., see Stephens, K.G. B50 (1990) 368

Hahn, C., see Ebel, F. B50 (1990) 328
Hallak, A.B., see Al-Juwair, H.A. B50 (1990) 474
Haller, M., see Baumgärtner, M. B50 (1990) 286
Hanson, A.L., see Kwiatek, W.M. B50 (1990) 347
Hare, G., S. Craig, J.-P. Labrie, C.B. Lawrence, J. Ungrin and B. White, Energy control of the IMPELA™ series of industrial accelerators B50 (1990) 470
Hayashi, N., see Johansen, A. B50 (1990) 119
Heimgartner, P., see Neumann, W. B50 (1990) 57
Heinrich, B., see Lück, H.B. B50 (1990) 395
Heiser, C., see Neelmeijer, C. B50 (1990) 439
Hemment, P.L.F., see Stephens, K.G. B50 (1990) 368
Herrmann, F., see Neelmeijer, C. B50 (1990) 439
Herrmann, R., see Hofmann, D. B50 (1990) 478
Höfert, M., see Rokita, E. B50 (1990) 217

Hofmann, D., H. Baumann, C. Freudenberger, R. Herrmann, A. Schempp, H. Schmidt-Böcking, G. Zschornack, K. Bethge, H. Klein, C. Lyneis and R. Stock, An ECR–RFQ ion beam facility for materials research with highly charged slow ions B50 (1990) 478
Hollos, G., see Boaretto, E. B50 (1990) 280
Höpfl, R., see Baumgärtner, M. B50 (1990) 286
Hult, M. and K. Themner, Quantitative microanalysis of matrix elements in biological samples by MeV proton scattering B50 (1990) 154

Izsak, K., see Maisch, T. B50 (1990) 1

Jaffrezic, H., see El Khakani, M.A. B50 (1990) 406
Jaffrezic, H., see Donnet, C. B50 (1990) 410
Jaffrezic, H., see El Bouanani, M. B50 (1990) 431
Jans, S., see Maisch, T. B50 (1990) 1
Jarczyk, L., see Rokita, E. B50 (1990) 217
Johansen, A., E. Johnson, L. Sarholt-Kristensen, S. Steenstrup, E. Gerritsen, C.J.M. Denissen, H. Keetels, J. Politiek, N. Hayashi and I. Sakamoto, Depth distribution of martensite in xenon-implanted stainless steels . B50 (1990) 119
Johnson, E., see Johansen, A. B50 (1990) 119
Jones, K.W., see Kwiatek, W.M. B50 (1990) 347

Kalbitzer, S., see Maisch, T. B50 (1990) 1
Kankeleit, E., see Müller, G. B50 (1990) 384
Karschnick, R., see Baumgärtner, M. B50 (1990) 286
Kato, K., see Faestermann, H. B50 (1990) 275
Katsaros, A., see Cohen, D.D. B50 (1990) 43
Keetels, H., see Johansen, A. B50 (1990) 119
Keinonen, J. and J. Räisänen, Analysis of Cu and O in high-T_c superconductors by 7–9 MeV protons B50 (1990) 39
Klein, H., see Hofmann, D. B50 (1990) 478
Klein, S.S., P.H.A. Mutsaers and B.E. Fischer, Mass selection and depth profiling by coincident recoil detection for nuclei in the middle mass region B50 (1990) 150
Klingelhöfer, G., see Müller, G. B50 (1990) 384
Kliský, V., The irradiation laboratory at ČKD Semiconductors Praha B50 (1990) 420
Köhl, F., J. Krauskopf, P. Misaelides, R. Michelmann, G. Wolf and K. Bethge, Determination of nitrogen in semiconductor materials using the $^{14}N(p, \alpha)^{11}C$ and $^{14}N(d, n)^{15}O$ nuclear reactions B50 (1990) 19
Korschinek, G., see Müller, D. B50 (1990) 271
Korschinek, G., see Faestermann, H. B50 (1990) 275
Krauskopf, J., see Köhl, F. B50 (1990) 19
Krauthan, P., see Faestermann, H. B50 (1990) 275
Kretschmer, W., see Baumgärtner, M. B50 (1990) 286
Kucha, H., see Przybyłowicz, W. B50 (1990) 231
Kutschera, W., Accelerator mass spectrometry: A versatile tool for research B50 (1990) 252
Kwiatek, W.M., A.L. Hanson and K.W. Jones, Selection of the experimental conditions for white-light SRIXE measurements B50 (1990) 347

Labohm, F., see Boerma, D.O. B50 (1990) 291
Labrie, J.-P., A standing-wave structure for a synchrotron ring injector B50 (1990) 465
Labrie, J.-P., see Hare, G. B50 (1990) 470
Lambrecht, D., see Weber, J. B50 (1990) 221
Lawrence, C.B., see Hare, G. B50 (1990) 470
Leitão, E., see Da Silva, R.C. B50 (1990) 423
Leoni, V., see Bizzarri, U. B50 (1990) 331
Lieb, K.P., W. Bolse, T. Corts, W. Müller, T. Osipowicz and T. Weber, Depth profiling of heavy-ion-mixed TiN films B50 (1990) 10
Lieb, K.P., see Weber, T. B50 (1990) 95
Lieb, K.-P., see Osipowicz, T. B50 (1990) 238
Loepfe, R., see Schaelin, A. B50 (1990) 379
Lohmann, W., see Bolse, W. B50 (1990) 416
Lubig, A., C. Buchal, J. Fröhlingsdorf, W. Zander and B. Stritzker, RBS investigations of buffer layers between $YBa_2Cu_3O_{7-x}$ and silicon B50 (1990) 114
Lucas, S., G. Terwagne and F. Bodart, Temperature and dose dependences of nitrogen implantation into aluminium B50 (1990) 401

Lück, H.B., H. Matthes, B. Gemende, B. Heinrich, W. Pfestorf, W. Seidel and S. Turuc, Production of particle-track membranes by means of a 5 MV tandem accelerator B50 (1990) 395
Lyneis, C., see Hofmann, D. B50 (1990) 478

Mader, A., J.D. Meyer, P. Thee and K. Bethge, Investigations of lattice location and mobility of carbon in GaAs using the channeling technique B50 (1990) 35
Mahunka, I., see Ditrói, F. B50 (1990) 62
Maier, K., see Bauer, W. B50 (1990) 300
Maisch, T., V. Schüle, R. Günzler, P. Oberschachtsiek, M. Weiser, S. Jans, K. Izsak and S. Kalbitzer, Trace-impurity detection by Rutherford backscattering and nuclear resonance reactions B50 (1990) 1
Major, J., see Bauer, W. B50 (1990) 300
Marble, D.K., see Anthony, J.M. B50 (1990) 262
Marest, G., see El Khakani, M.A. B50 (1990) 406
Marest, G., see Donnet, C. B50 (1990) 410
Massiot, P., see Tirira, J. B50 (1990) 135
Massiot, P., see Trocellier, P. B50 (1990) 247
Mathot, S. and G. Demortier, Silicon diffusion in gold grain boundaries studied with a deuteron microbeam .. B50 (1990) 52
Matteson, S.E., see Anthony, J.M. B50 (1990) 262
Matthes, H., see Lück, H.B. B50 (1990) 395
McDaniel, F.C., see Anthony, J.M. B50 (1990) 262
Melchior, H., see Schaelin, A. B50 (1990) 379
Melo, A.A., see Da Silva, R.C. B50 (1990) 423
Messina, G., see Bizzarri, U. B50 (1990) 331
Meyer, J.D., see Mader, A. B50 (1990) 35
Meyer, J.D. and D.E. Arafah, Influence of electronic charge compensation on Rutherford backscattering spectra of biased insulators B50 (1990) 109
Meyer, J.D., see Stanescu, T.M. B50 (1990) 167
Michelmann, R., see Köhl, F. B50 (1990) 19
Milinković, L.S., see Subotić, K.M. B50 (1990) 267
Milosavljević, M., see Stojanović, M.S. B50 (1990) 102
Milosavljević, M., N. Bibić, D. Perušk, K.M. Stojanović and I.H. Wilson, Analysis of annealing and ion implantation effects in Ti/TiN contacts on silicon B50 (1990) 391
Misaelides, P., see Köhl, F. B50 (1990) 19
Mohammedein, A.M.M., see Fritzsche, S. B50 (1990) 353
Möller, W., see Wielunski, M. B50 (1990) 23
Mommsen, H., see Weber, J. B50 (1990) 221
Moncoffre, N., see El Khakani, M.A. B50 (1990) 406
Moncoffre, N., see Donnet, C. B50 (1990) 410
Mori, V., see Tirira, J. B50 (1990) 135
Mosbah, M., see Trocellier, P. B50 (1990) 247
Moseley, S.H., see Woiwod, S. B50 (1990) 91
Mueller, R.M., see Woiwod, S. B50 (1990) 91
Müller, D., T. Faestermann, A. Gillitzer, G. Korschinek, R. Scheuer and U. Bittner, Accelerator mass spectrometry with time-of-flight measurement B50 (1990) 271
Müller, G., G. Klingelhöfer, P. Schwalbach and E. Kankeleit, High-dose iron implantation into silicon and metals B50 (1990) 384
Müller, W., see Lieb, K.P. B50 (1990) 10
Münzer, H., see Neelmeijer, C. B50 (1990) 439
Musiol, G., see Fritzsche, S. B50 (1990) 353
Mutsaers, P.H.A., see Klein, S.S. B50 (1990) 150

Neelmeijer, C., B. Schmidt, W. Rudolph, H. Münzer, D. Grambole, C. Heiser and F. Herrmann, PECVD Si nitride and Si oxide layers – hydrogen analysis and etching after ion implantation B50 (1990) 439
Neumann, W., W. Woelfli, P. Heimgartner and R.M. Streicher, Thin-layer activation of hip-joint prostheses for tribological tests B50 (1990) 57
Nolte, E., see Faestermann, H. B50 (1990) 275
Novković, D., see Stojanović, M.S. B50 (1990) 102
Novković, D., see Subotić, K.M. B50 (1990) 267

Oberschachtsiek, P., see Maisch, T. B50 (1990) 1
Omarini, S., see Bizzarri, U. B50 (1990) 331

Osipowicz, T., see Lieb, K.P. B50 (1990) 10
Osipowicz, T., T. Corts, K.-...P. Lieb and F.-J. Bergmeister, PIXE measurements of Kr-sputtered TiN coatings B50 (1990) 238
Ottermann, C., see Wagner, W. B50 (1990) 27
Otto, G., see Zschau, H.-E. B50 (1990) 74

Pantenburg, F.J., see Weber, J. B50 (1990) 221
Pape, A., see Georgiadis, A.P. B50 (1990) 321
Park, M.A., see Schweikert, E.A. B50 (1990) 307
Parmigiani, F., see Cereda, E. B50 (1990) 48
Parmigiani, F., see Boni, C. B50 (1990) 243
Paul, M., see Boaretto, E. B50 (1990) 280
Peruško, D., see Milosavljević, M. B50 (1990) 391
Pfestorf, W., see Lück, H.B. B50 (1990) 395
Picardi, L., see Bizzarri, U. B50 (1990) 331
Piestrzyński, A., see Przybyłowicz, W. B50 (1990) 231
Plier, F., see Zschau, H.-E. B50 (1990) 74
Politiek, J., see Johansen, A. B50 (1990) 119
Pretorius, R. and D. Bezuidenhout, Characterization of optical coatings by Rutherford backscattering spectrometry and elastic recoil detection analysis B50 (1990) 105
Przybyłowicz, W., H. Kucha, A. Piestrzyński, K. Traxel and S. Bajt, Micro-PIXE analyses of trace elements in black shales from the lower Zechstein copper deposits, Poland B50 (1990) 231

Raimondi, P., see Bizzarri, U. B50 (1990) 331
Räisänen, J., see Keinonen, J. B50 (1990) 39
Rajeh, M., see Al-Juwair, H.A. B50 (1990) 474
Rauch, F., see Wagner, W. B50 (1990) 27
Rauscher, A., see Baumgärtner, M. B50 (1990) 286
Rebouta, L., J.C. Soares, M.F. Da Silva, J.A. Sanz-Garcia, E. Diéguez and F. Agulló-López, Determination of lattice sites for Eu, Hf and Nd in $LiNbO_3$ by RBS/channeling experiments B50 (1990) 428
Reeson, K.J., see Stephens, K.G. B50 (1990) 368
Reiche, I., see Fritzsche, S. B50 (1990) 353
Reichle, R., R. Behrisch and J. Roth, Depth-profiling of beryllium on graphite with ion beams B50 (1990) 68
Reinders, J.A., see Boerma, D.O. B50 (1990) 291
Respaldiza, M.A., F. Barranco, J. Gómez-Camacho, B.M. Gómez-Tubío and M.M. Ruiz-Delgado, Combining PIXE and XRF with gamma-ray transmission to get accurate analysis of archaeological bronzes B50 (1990) 226
Rietveld, P., see Wätjen, U. B50 (1990) 172
Rokita, E., T. Cichocki, S. Divoux, B. Gonsior, M. Höfert, L. Jarczyk, A. Strzalkowski and M. Sych, Proton microprobe studies of the mineralization process in selected organic matrices B50 (1990) 217
Roland, G., H. Baumann and K. Bethge, RBS analysis of GaAs and InP after electron beam annealing B50 (1990) 145
Ronsivalle, C., see Bizzarri, U. B50 (1990) 331
Roth, J., see Reichle, R. B50 (1990) 68
Rückert, M., see Ebel, F. B50 (1990) 328
Rudolph, W., see Neelmeijer, C. B50 (1990) 439
Rühm, W., see Faestermann, H. B50 (1990) 275
Ruiz-Delgado, M.M., see Respaldiza, M.A. B50 (1990) 226

Sakamoto, I., see Johansen, A. B50 (1990) 119
Santoro, G., see Tuniz, C. B50 (1990) 338
Sanz-Garcia, J.A., see Rebouta, L. B50 (1990) 428
Sarholt-Kristensen, L., see Johansen, A. B50 (1990) 119
Scagliotti, M., see Cereda, E. B50 (1990) 48
Scagliotti, M., see Boni, C. B50 (1990) 243
Schaefer, H.-E., see Bauer, W. B50 (1990) 300
Schaelin, A., R. Loepfe, H. Melchior, M. Suter and W. Woelfli, Beryllium bombardment for $In_{0.53}Ga_{0.47}As$ and InP photoconductors with picosecond response times B50 (1990) 379
Schempp, A., RFQ accelerators for ion implantation B50 (1990) 460
Schempp, A., see Hofmann, D. B50 (1990) 478
Scheuer, R., see Müller, D. B50 (1990) 271
Schleicher, M., see Baumgärtner, M. B50 (1990) 286
Schmidt, B., see Neelmeijer, C. B50 (1990) 439
Schmidt-Böcking, H., see Hofmann, D. B50 (1990) 478

Schneider, H., see Ebel, F. B50 (1990) 328
Schroyen, D., see Wätjen, U. B50 (1990) 172
Schubert, F., see Fritzsche, S. B50 (1990) 353
Schüle, V., see Maisch, T. B50 (1990) 1
Schuster, W., see Baumgärtner, M. B50 (1990) 286
Schwalbach, P., see Müller, G. B50 (1990) 384
Schweikert, E.A., M.G. Blain, M.A. Park and E.F. Da Silveira, Surface characterization with keV clusters and MeV ions B50 (1990) 307
Sealy, B.J., see Stephens, K.G. B50 (1990) 368
Seeger, A., see Bauer, W. B50 (1990) 300
Seidel, W., see Lück, H.B. B50 (1990) 395
Singe, A., see Ebel, F. B50 (1990) 328
Soares, J.C., see Da Silva, R.C. B50 (1990) 423
Soares, J.C., see Rebouta, L. B50 (1990) 428
Sokhi, R.S., P.W. Gilberd and L.G. Earwaker, Investigation of films of $YBa_2Cu_3O_7$ using Rutherford backscattering spectrometry B50 (1990) 140
Stanescu, T.M., J.D. Meyer, H. Baumann and K. Bethge, Time-of-flight spectrometry for materials analysis . . . B50 (1990) 167
Steenstrup, S., see Johansen, A. B50 (1990) 119
Steiger, J., O. Boebel, M. Briere, A. Weidinger and P. Ziegler, Hydrogen profiling of Nb–Hf–Nb layers by the ^{15}N method B50 (1990) 31
Stephens, K.G., K.J. Reeson, B.J. Sealy, R.M. Gwilliam and P.L.F. Hemment, The formation of compound layers in silicon by ion beam synthesis B50 (1990) 368
Stern, M., see El Bouanani, M. B50 (1990) 431
Stock, R., see Hofmann, D. B50 (1990) 478
Stojanović, M.S., M. Milosavljević, K.M. Subotić, F. Boreli, I.H. Wilson and D. Novković, RBS analysis of front contacts for surface-barrier detectors B50 (1990) 102
Stojanović, M.S., see Subotić, K.M. B50 (1990) 267
Stojanović, M.S., see Milosavljević, M. B50 (1990) 391
Stoll, H., see Bauer, W. B50 (1990) 300
Streicher, R.M., see Neumann, W. B50 (1990) 57
Stritzker, B., see Woiwod, S. B50 (1990) 91
Stritzker, B., see Lubig, A. B50 (1990) 114
Strzalkowski, A., see Rokita, E. B50 (1990) 217
Subotić, K.M., see Stojanović, M.S. B50 (1990) 102
Subotić, K.M., D. Novković, M.S. Stojanović and L.S. Milinković, Superconducting minicyclotrons in AMS . . B50 (1990) 267
Suter, M., see Schaelin, A. B50 (1990) 379
Sych, M., see Rokita, E. B50 (1990) 217

Takács, S., see Ditrói, F. B50 (1990) 62
Teesdale, W.J., see Campbell, J.L. B50 (1990) 189
Terwagne, G., see Lucas, S. B50 (1990) 401
Thee, P., see Mader, A. B50 (1990) 35
Themner, K., see Hult, M. B50 (1990) 154
Theunissen, A.M.L., see Van Ijzendoorn, L.J. B50 (1990) 127
Thomae, R.W., Recent developments in ion implantation accelerators B50 (1990) 444
Tirira, J., P. Trocellier, J.P. Frontier, P. Massiot, J.M. Costantini and V. Mori, 3D hydrogen profiling by elastic recoil detection analysis in transmission geometry B50 (1990) 135
Tirira, J., see Trocellier, P. B50 (1990) 247
Tobehn, I., see Ebel, F. B50 (1990) 328
Toulhoat, N., see Trocellier, P. B50 (1990) 247
Tousset, J., see El Khakani, M.A. B50 (1990) 406
Tousset, J., see Donnet, C. B50 (1990) 410
Traxel, K., Nuclear microbeams: Realization and use as scientific tool B50 (1990) 177
Traxel, K., see Przybyłowicz, W. B50 (1990) 231
Treide, A., see Zschau, H.-E. B50 (1990) 74
Trocellier, P., see Tirira, J. B50 (1990) 135
Trocellier, P., M. Mosbah, N. Toulhoat, J. Tirira, J. Gosset, P. Massiot and C. Engelmann, Seven years of research using the Bruyères Le Châtel microprobe facility: A review B50 (1990) 247
Tros, G.H.J., F. Van Langevelde and R.D. Vis, On the analysis of neonatal hamster tooth germs with the photon microprobe at Daresbury, UK B50 (1990) 343
Tuniz, C., R. Devoti, G. Santoro and F. Zanini, A synchrotron radiation microprobe for X-ray fluorescence and microtomography at ELETTRA B50 (1990) 338

Turuc, S., see Lück, H.B. B50 (1990) 395

Ungrin, J., see Hare, G. B50 (1990) 470

Van de Walle, G.F.A., see Van Ijzendoorn, L.J. B50 (1990) 127
Van den Heuvel, R.A., see Van Ijzendoorn, L.J. B50 (1990) 127
Van Gorkum, A.A., see Van Ijzendoorn, L.J. B50 (1990) 127
Van Ijzendoorn, L.J., G.F.A. Van de Walle, A.A. Van Gorkum, A.M.L. Theunissen, R.A. Van den Heuvel and J.H. Barrett, Diffusion and strain relaxation in $Si/Si_{1-x}Ge_x/Si$ structures studied with Rutherford backscattering spectrometry B50 (1990) 127
Van Langevelde, F., see Tros, G.H.J. B50 (1990) 343
Van Oosterhout, H.A.P., A new generation of single-ended Van de Graaff accelerators for ion implantation and ion beam analysis B50 (1990) 455
Vignati, A., see Bizzarri, U. B50 (1990) 331
Vis, R.D., see Tros, G.H.J. B50 (1990) 343
Vourkas, M., see Georgiadis, A.P. B50 (1990) 321

Wagner, W., F. Rauch, C. Ottermann and K. Bange, Hydrogen dynamics in electrochromic multilayer systems investigated by the ^{15}N technique B50 (1990) 27
Wang, J.-X., see Campbell, J.L. B50 (1990) 189
Wätjen, U., D. Schroyen, E. Bombelka and P. Rietveld, Thin reference layers available for calibration purposes in ion beam analysis B50 (1990) 172
Watt, F., see Grime, G.W. B50 (1990) 197
Weber, J., T. Beier, U. Diehl, D. Lambrecht, H. Mommsen and F.J. Pantenburg, A PIXE mini-beam setup at the Bonn cyclotron for archeometric metal analyses B50 (1990) 221
Weber, T., see Lieb, K.P. B50 (1990) 10
Weber, T., W. Bolse and K.P. Lieb, RBS analyses of xenon-irradiated Ti and TiN films B50 (1990) 95
Weber, T., see Bolse, W. B50 (1990) 416
Weidinger, A., see Steiger, J. B50 (1990) 31
Weiser, M., see Maisch, T. B50 (1990) 1
Wesch, W., see Götz, G. B50 (1990) 131
White, B., see Hare, G. B50 (1990) 470
Widmann, E., see Bauer, W. B50 (1990) 300
Wielunski, M. and W. Möller, A simple coincidence method of deuterium profiling using the $D(^3He, \alpha)H$ reaction B50 (1990) 23
Wilpert, M., see Gebauer, B. B50 (1990) 159
Wilpert, T.H., see Gebauer, B. B50 (1990) 159
Wilson, I.H., see Stojanović, M.S. B50 (1990) 102
Wilson, I.H., see Milosavljević, M. B50 (1990) 391
Woelfli, W., see Neumann, W. B50 (1990) 57
Woelfli, W., see Schaelin, A. B50 (1990) 379
Woiwod, S., R.M. Mueller, B. Stritzker and S.H. Moseley, A low-temperature bolometer for particle detection in Rutherford backscattering analysis B50 (1990) 91
Wolf, G., see Köhl, F. B50 (1990) 19
Wyrwich, C., see Zschau, H.-E. B50 (1990) 74

Zander, W., see Lubig, A. B50 (1990) 114
Zanini, F., see Tuniz, C. B50 (1990) 338
Zerle, L., see Faestermann, H. B50 (1990) 275
Ziegler, P., see Steiger, J. B50 (1990) 31
Zschau, H.-E., F. Plier, G. Otto, C. Wyrwich and A. Treide, Fluorine profiling after application of various anti-caries gels B50 (1990) 74
Zschornack, G., see Fritzsche, S. B50 (1990) 353
Zschornack, G., see Hofmann, D. B50 (1990) 478